

Notice of References Cited	Application/Control No. 10/580,648	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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*	N	JP 2002-347107	04-2002	Japan	Shimomura et al	
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NON-PATENT DOCUMENTS

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